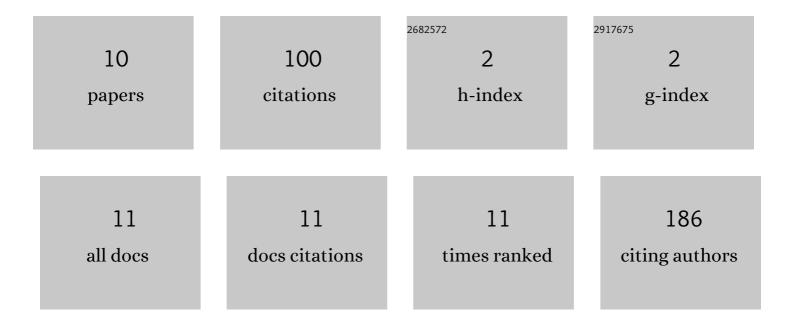
## Shubhakar Kalya

List of Publications by Year in descending order

Source: https://exaly.com/author-pdf/6235860/publications.pdf Version: 2024-02-01



SHIIRHAKAD KAIVA

#	Article	IF	CITATIONS
1	Reliability and Breakdown Study of Erase Gate Oxide in Split-Gate Non-Volatile Memory Device. , 2020, , .		ο
2	Boron Vacancies Causing Breakdown in 2D Layered Hexagonal Boron Nitride Dielectrics. IEEE Electron Device Letters, 2019, 40, 1321-1324.	3.9	16
3	Dielectric Breakdown in 2D Layered Hexagonal Boron Nitride — The Knowns and the Unknowns. , 2019, , .		2
4	Conductive Atomic Force Microscope Study of Bipolar and Threshold Resistive Switching in 2D Hexagonal Boron Nitride Films. Scientific Reports, 2018, 8, 2854.	3.3	55
5	Mechanism of soft and hard breakdown in hexagonal boron nitride 2D dielectrics. , 2018, , .		10
6	Nanoscale investigations of soft breakdown events in few layered fluorinated graphene. , 2017, , .		0
7	Multiphysics based 3D percolation framework model for multi-stage degradation and breakdown in high-lº — Interfacial layer stacks. , 2016, , .		2
8	Observation of resistive switching by physical analysis techniques. , 2016, , .		0
9	Understanding the switching mechanism in RRAM using in-situ TEM. , 2016, , .		5
10	CAFM based spectroscopy of stress-induced defects in HfO <inf>2</inf> with experimental		10

evidence of the clustering model and metastable vacancy defect state. , 2016, , .